


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509745	<b>Applicant(s)/Patent Under Reexamination</b>  KAWAGUCHI ET AL.
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched using EAST and also relied on international search report (ISR) and asked questions during QEM meeting. Some of the subclasses searched are 369/275.1, 428/66.6, 64.9 (text search only - look at search report printout)	08/16/07	Henok Heyi
Updated search	05/07/2008	Henok Heyi
Updated search.	10/09/2008	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/ Examiner.Art Unit 2627	
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